

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/664,637	HANEY ET AL.
	Examiner	Art Unit
	David E. Bochna	3679

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
285	390, 333	8/22/2006	DB
	334, 115		
	423		